

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS5002	Jan-96	9525 M3	ANAM, K.	DN507368AAH	1.2μ OX/NI	80 PQFP

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-16826

<u>Electrical</u>	<u>Cum %</u>
163/0	0.0%

Sonoscan
P-16833

<u>Post Vapor Phase</u>
2/2
F1

Infant / High Voltage Life
125°C, 7.0 V.
P-16834, P-16864

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
161/0	42/0	42/1	119 Fits
		F2	

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-16865

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
39/0	39/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-16866

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
42/0	42/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-16867

<u>96 Hr</u>	<u>Cum %</u>
38/0	0.0%

Failure Mode

F1: 2-Delamination

F2: 1-Battest